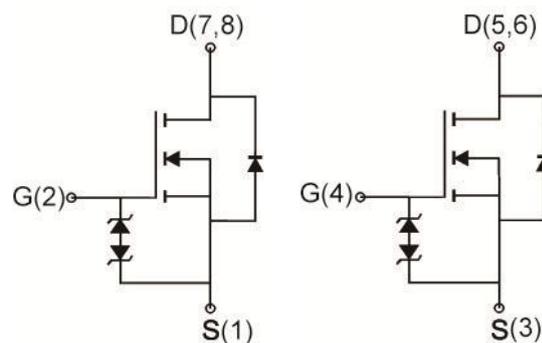
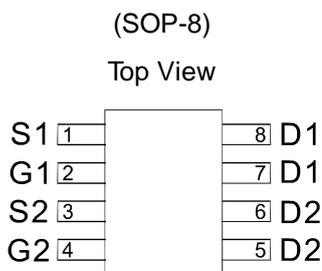


Dual N-Channel 30-V (D-S) MOSFET, ESD Protection

GENERAL DESCRIPTION

The ME4920D-G is the Dual N-Channel logic enhancement mode power field effect transistors, using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on state resistance. These devices are particularly suited for low voltage application such as cellular phone, notebook computer power management and other battery powered circuits, and low in-line power loss that are needed in a very small outline surface mount package.

PIN CONFIGURATION



FEATURES

- $R_{DS(ON)} \leq 30 \text{ m}\Omega @ V_{GS}=10\text{V}$
- $R_{DS(ON)} \leq 40 \text{ m}\Omega @ V_{GS}=4.5\text{V}$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

Ordering Information: ME4920D (Pb-free)

ME4920D-G (Green product-Halogen free)

Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Parameter	Symbol	Maximum Ratings	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	$T_A=25^\circ\text{C}$	6.7
		$T_A=70^\circ\text{C}$	5.3
Pulsed Drain Current	I_{DM}	27	A
Continuous Source Current (Diode Conduction)	I_S	1.7	A
Maximum Power Dissipation	P_D	$T_A=25^\circ\text{C}$	2
		$T_A=70^\circ\text{C}$	1.3
Operating Junction Temperature	T_J	-55 to 150	$^\circ\text{C}$
Thermal Resistance-Junction to Ambient*	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$

The device mounted on 1in² FR4 board with 2 oz copper



Dual N-Channel 30-V (D-S) MOSFET, ESD Protection Electrical Characteristics (TA=25°C Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μA	30			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 μA	1		3	V
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±16V			±10	μA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V			±1	
R _{DS(ON)}	Drain-Source On-Resistance	V _{GS} =10V, I _D = 6.9A		23	30	mΩ
		V _{GS} =4.5V, I _D = 5.8A		34	45	
V _{SD}	Diode Forward Voltage	I _S =6.9A, V _{GS} =0V		0.8	1.2	V
DYNAMIC^b						
Q _g	Total Gate Charge	V _{DS} =15V, V _{GS} =10V, I _D =6.9A		11		nC
Q _{gs}	Gate-Source Charge			3		
Q _{gd}	Gate-Drain Charge			2		
C _{iss}	Input Capacitance	V _{DS} =15V, V _{GS} =0V, f=1MHz		360		pF
C _{oss}	Output Capacitance			67		
C _{rss}	Reverse Transfer Capacitance			20		
t _{d(on)}	Turn-On Delay Time	V _{DD} =15V, R _L =15Ω I _D =1A, V _{GEN} =10V R _G =6Ω		9.6		ns
t _r	Turn-On Rise Time			12		
t _{d(off)}	Turn-Off Delay Time			31		
t _f	Turn-Off Fall Time			3.7		

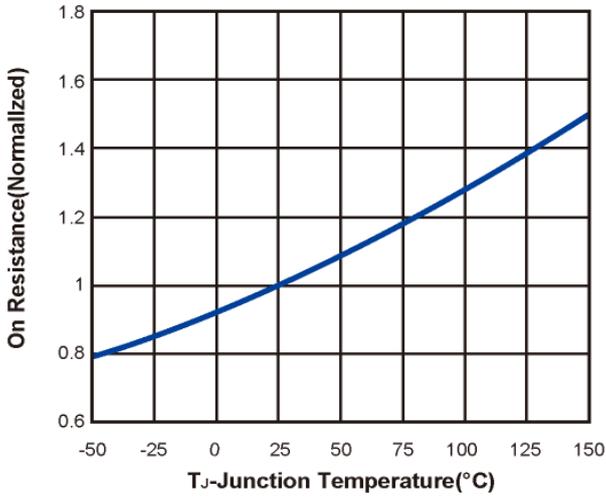
Notes: a. pulse test:pulse width ≤ 300us, duty cycle ≤ 2%,Guaranteed by design, not subject to production testing.

b. Matsuki Electric/ Force mos reserves the right to improve product design, functions and reliability without notice

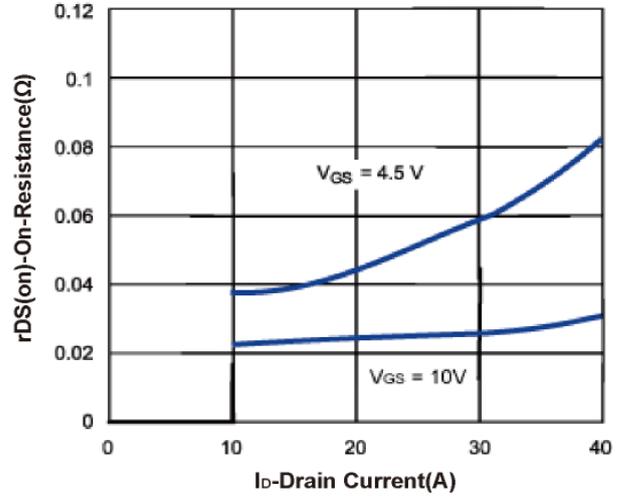


Dual N-Channel 30-V (D-S) MOSFET, ESD Protection
 Typical Characteristics (T_J = 25°C Noted)

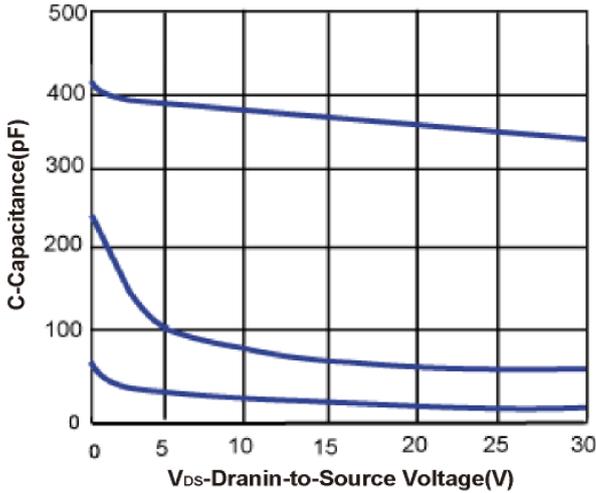
On Resistance vs. Junction Temperature



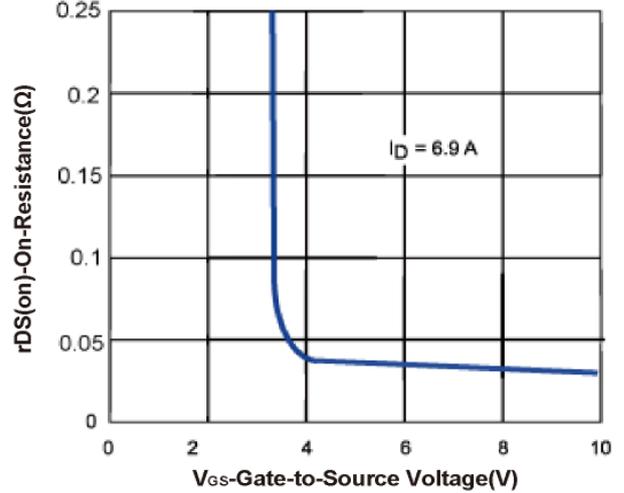
On Resistance vs. Drain Current



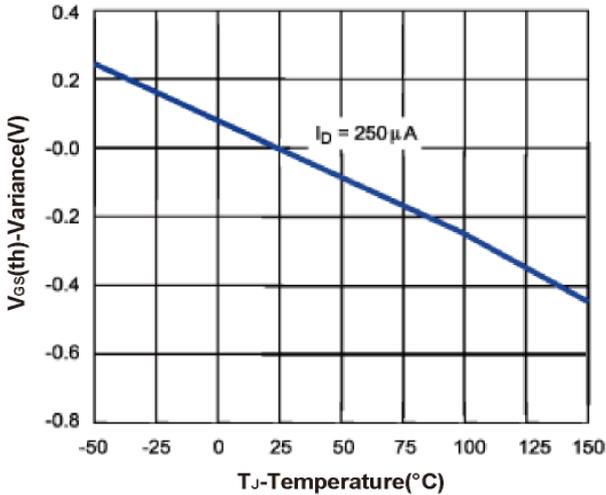
Capacitance



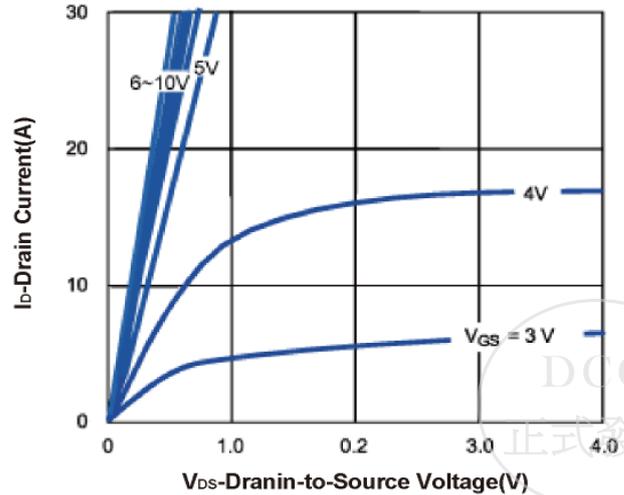
On Resistance vs. Gate-to-Source Voltage



Threshold Voltage

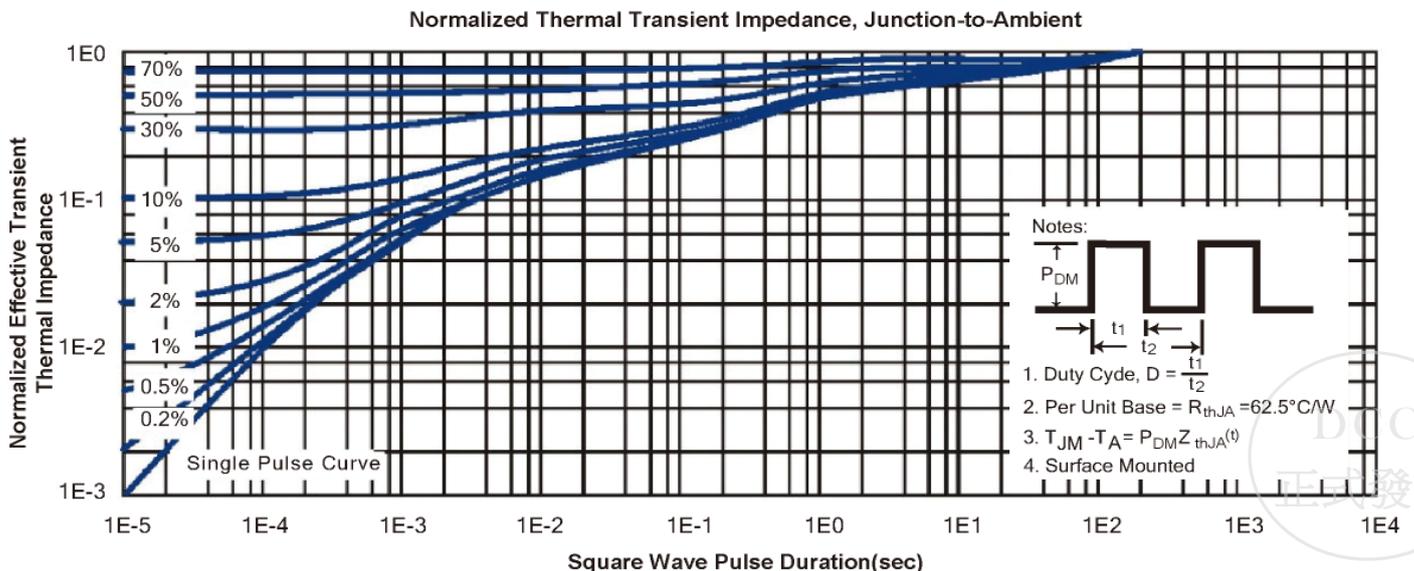
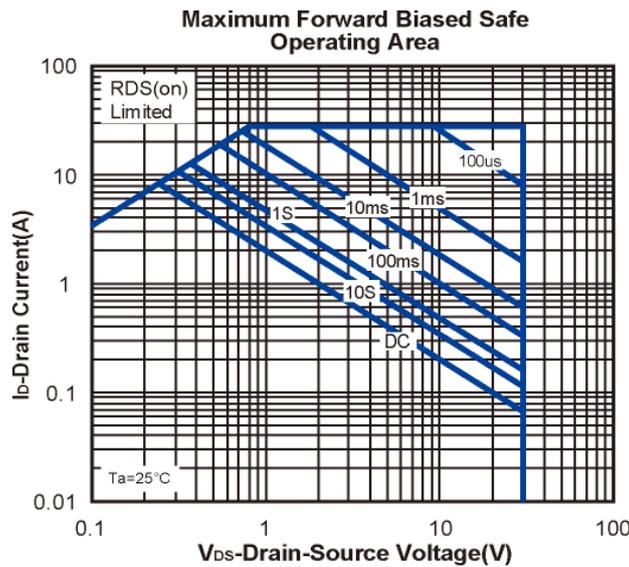
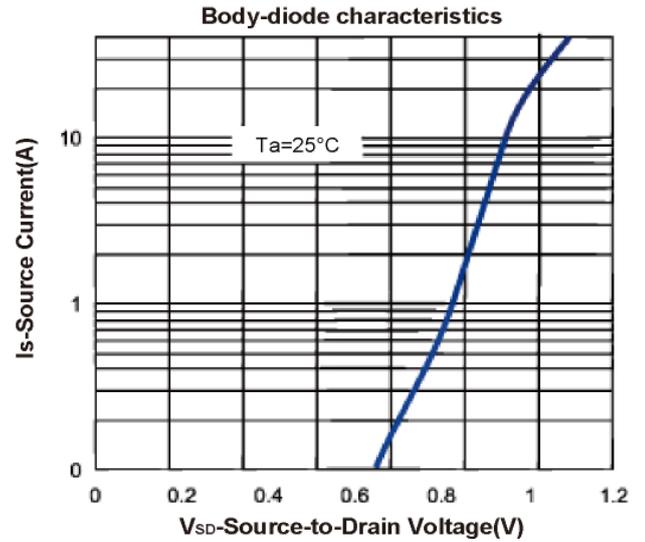
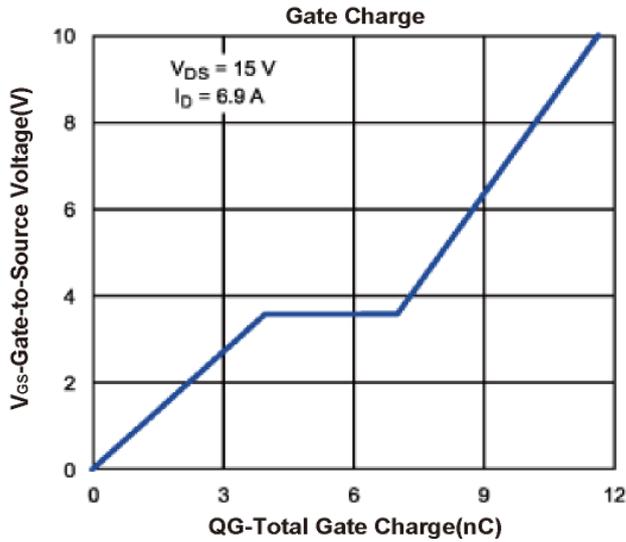


On-Region Characteristics

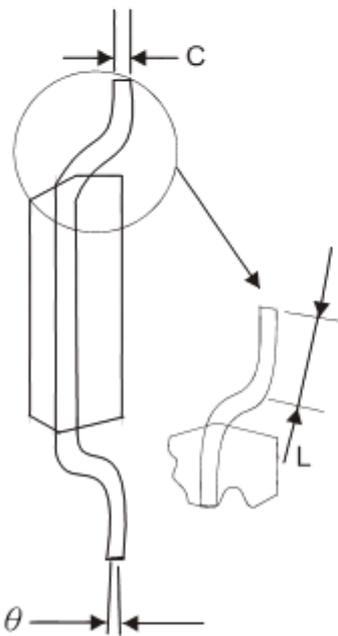
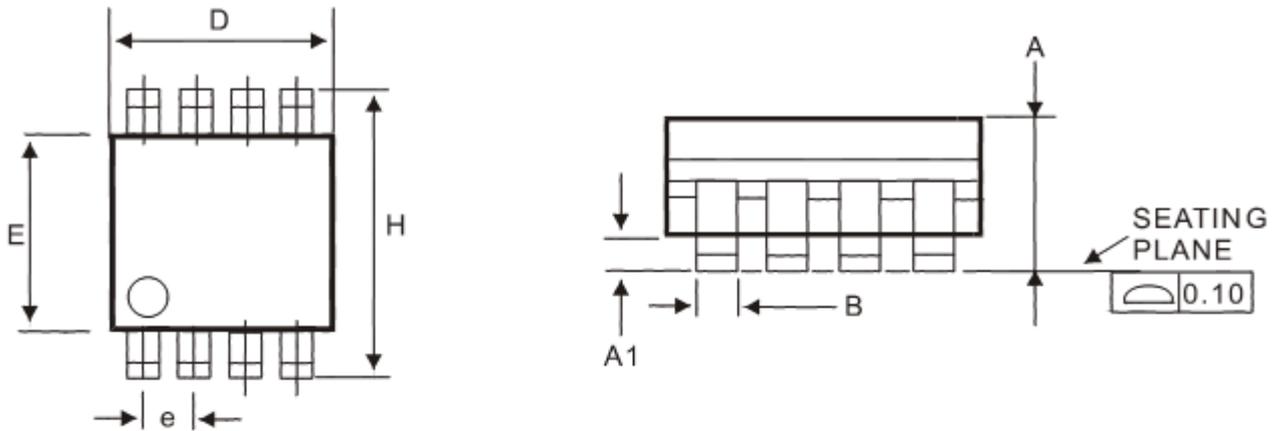


Dual N-Channel 30-V (D-S) MOSFET, ESD Protection

Typical Characteristics (T_J =25°C Noted)



SOP-8 Package Outline



DIM	MILLIMETERS(mm)	
	MIN	MAX
A	1.35	1.75
A1	0.10	0.25
B	0.35	0.49
C	0.18	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BSC	
H	5.80	6.20
L	0.40	1.25
θ	0°	7°

Note: 1. Refer to JEDEC MS-012AA.

2. Dimension "D" does not include mold flash, protrusions or gate burrs . Mold flash, protrusions or gate burrs shall not exceed 0.15 mm per side.

